

[54] **X-CONTROL MEASURING GAUGE**
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[73] **Assignee: Military Standards Corporation, Marina del Rey, Calif.**
[**] **Term: 14 Years**
[21] **Appl. No.: 437,993**
[22] **Filed: Nov. 20, 1989**
[52] **U.S. Cl. D10/70**
[58] **Field of Search D10/70, 71, 72; 73/1 R, 73/1 D**

[56] **References Cited**
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Attorney, Agent, or Firm—Cislo & Thomas

[57] **CLAIM**
The ornamental design for x-control measuring gauge, as shown and described.

DESCRIPTION
FIG. 1 is a perspective view with all sides being identical of a x-control measuring gauge showing my new design, drawn on a slightly enlarged scale;
FIG. 2 is a elevational view showing one of the four identical side views;
FIG. 3 is a top plan view; and
FIG. 4 is a bottom plan view thereof.

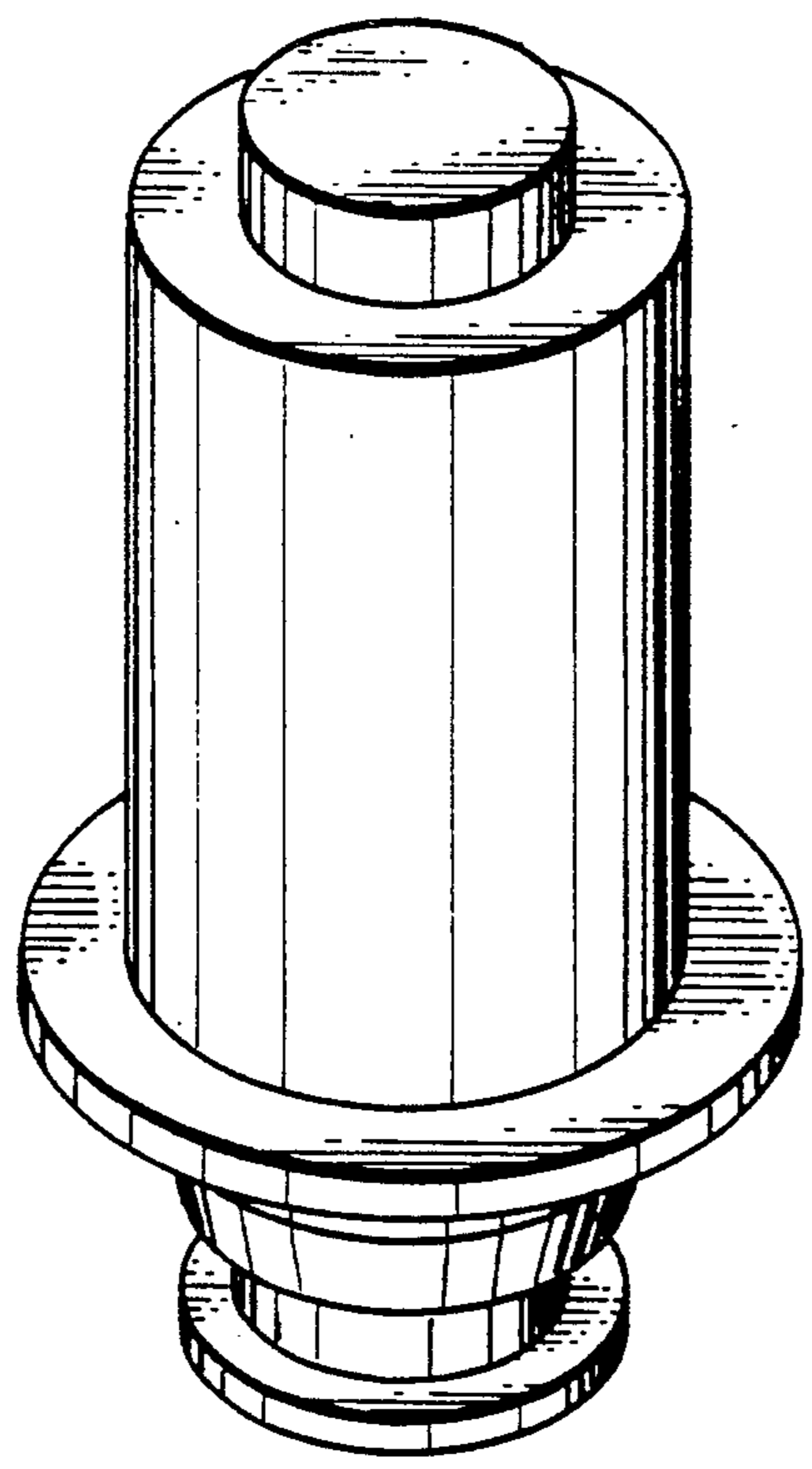


Fig. 1.

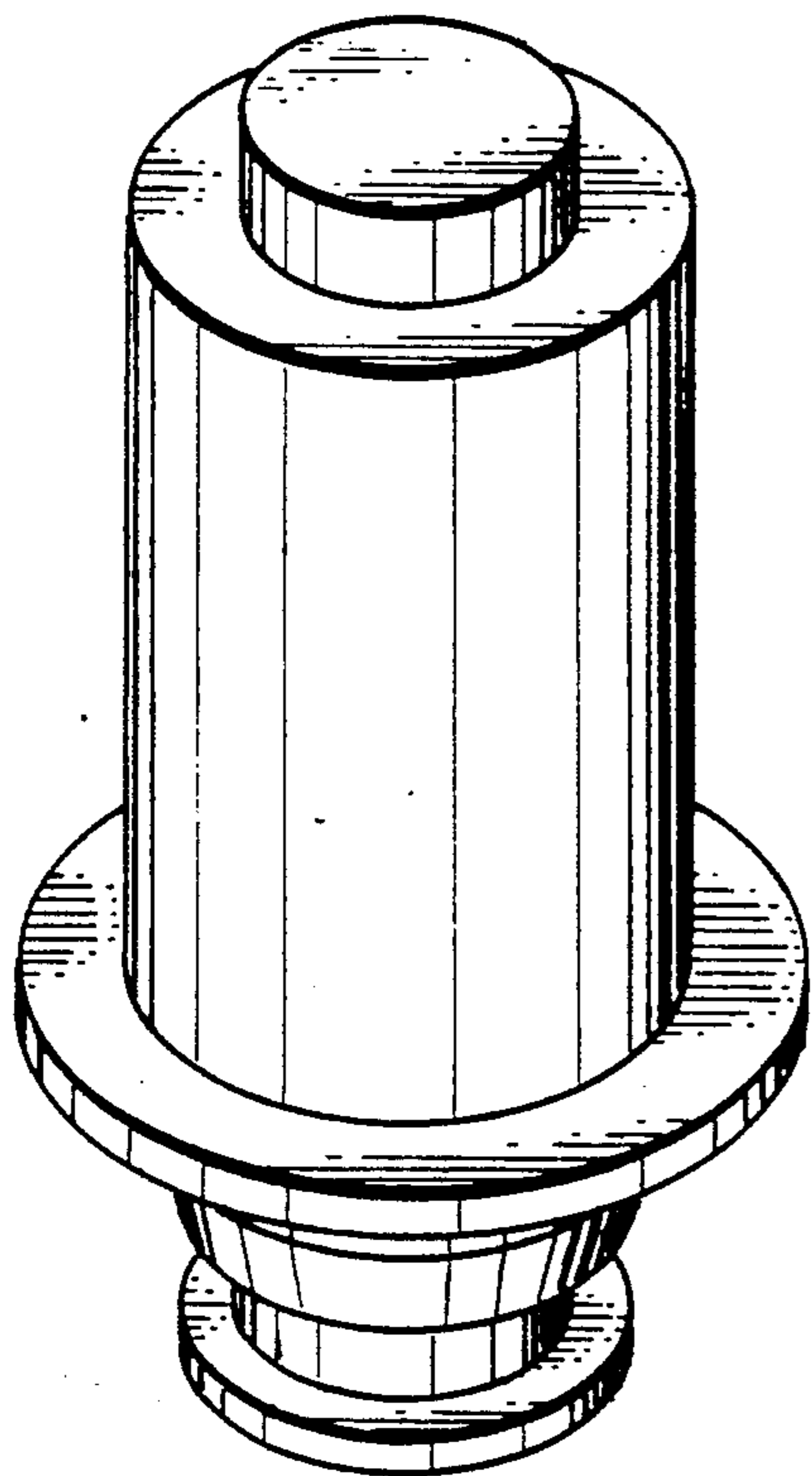


Fig. 2.

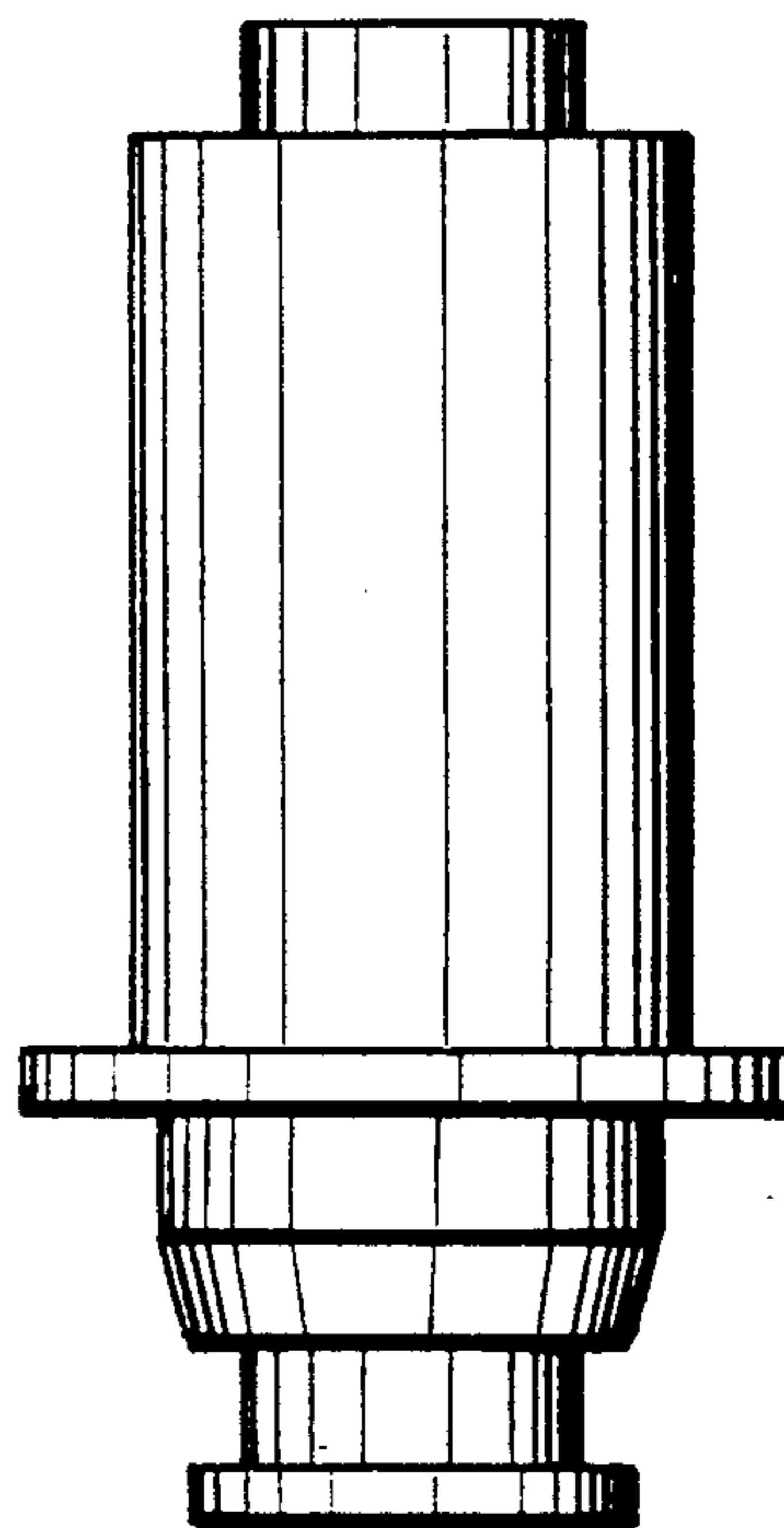


Fig. 3.

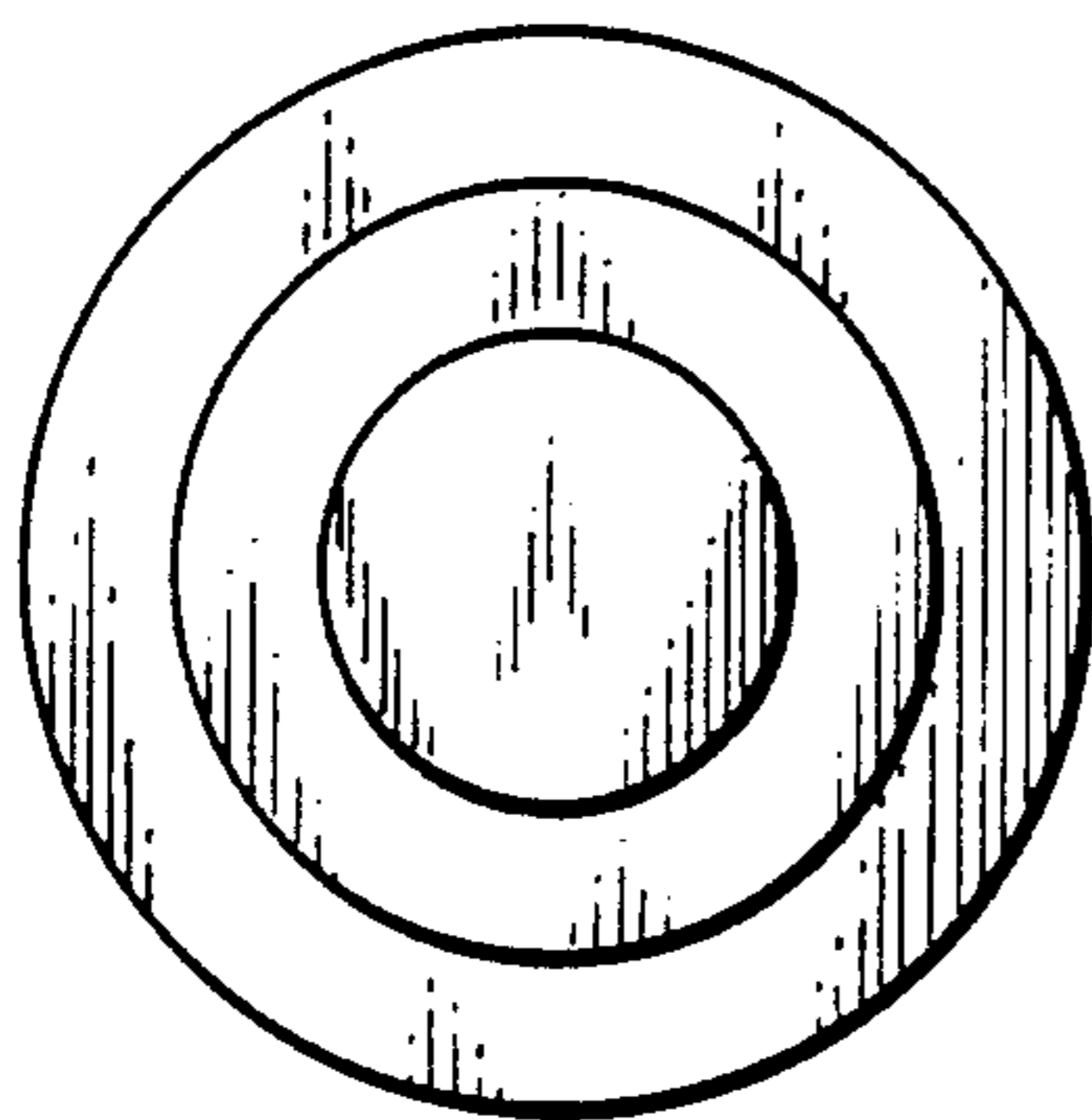


Fig. 4.

